

Short Course on RF Measurements for a Wireless World

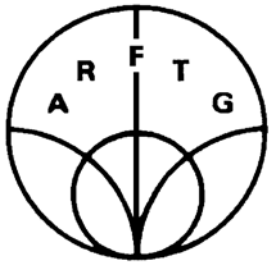
November 27-November 28, 2001
San Diego, California



AGENDA

Tuesday, November 27

- 7:30 a.m. – 8:00 a.m. **Registration**
- 8:00 a.m. – 9:15 a.m. **VNA Error Models and Calibration Methods**
Doug Rytting - Agilent
- 9:15 a.m. – 9:50 a.m. **RF Connectors and Transmission Lines**
John Juroshek – NIST
- 9:50 a.m. – 10:10 a.m. **Break**
- 10:10 a.m. – 10:45 a.m. **VNA Uncertainty**
John Juroshek - NIST
- 10:45 a.m. – 11:30 a.m. **Test Fixtures and Probing Techniques**
Leonard Hayden – Cascade Microtech
- 11:30 a.m. – 12:00 p.m. **Accurate On-Wafer Measurement**
Dave Walker/Dylan Williams - NIST
- 12:00 p.m. – 1:00 p.m. **Lunch**
- 1:00 p.m. – 2:15 p.m. **Broadband Measurements of VLSI Interconnects**
Uwe Arz – NIST
- 2:15 p.m. – 3:30 p.m. **Microwave Power Measurements**
Ken Harvey – Peak Consulting
- 3:30 p.m. – 3:50 p.m. **Break**
- 3:50 p.m. – 5:00 p.m. **Thermal Noise Measurements**
Jim Randa - NIST



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NIST

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Wednesday, November 28

- 8:00 a.m. – 8:50 a.m. **Uncertainty Analysis**
Nick Ridler – NPL
- 8:50 a.m. – 9:35 a.m. **Time Domain Network Analysis**
Dima Smolyansky – TDA Systems
- 9:35 a.m. – 10:15 a.m. **Introduction to Wireless Measurements**
Yves Rolain – Vrije Universiteit Brussel
- 10:15 a.m. – 10:30 a.m. **Break**
- 10:30 a.m. – 12:00 p.m. **Large-Signal Measurements**
*Marc Vanden Bossche, Jan Verspecht,
Frans Verbeyst – Agilent*